

**Document Title****128K x8 bit Low Power and Low Voltage CMOS Static RAM****Revision History**

<b><u>Revision No.</u></b>	<b><u>History</u></b>	<b><u>Draft Data</u></b>	<b><u>Remark</u></b>
0.0	Initial draft	July 3, 1996	Preliminary
1.0	Finalize - Increased I <sub>SB</sub> , I <sub>DR</sub> Commercial part = 10μA Industrial part = 20μA	December 16, 1996	Final
2.0	Revise - Change speed bin KM68V1000C Family: 70/85ns → 70/100ns KM68U1000C Family: 70/100ns → 85/100ns - Improved operating current: 40mA → 35mA - Improved power dissipation Pd: 0.7W → 1.0W - Improved standby current Extended/Industrial: 20 → 10μA - VIL: 0.4V → 0.6V	November 25, 1997	Final

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## 128K x8 bit Low Power and Low Voltage CMOS Static RAM

### FEATURES

- Process Technology: 0.4μm CMOS
- Organization: 128K x8
- Power Supply Voltage:
  - KM68V1000C family: 3.0~3.6V
  - KM68U1000C family: 2.7~3.3V
- Low Data Retention Voltage: 2V(Min)
- Three state output and TTL Compatible
- Package Type: 32-SOP-525, 32-TSOP1-0820F/R, 32-TSOP1-0813.4F/R

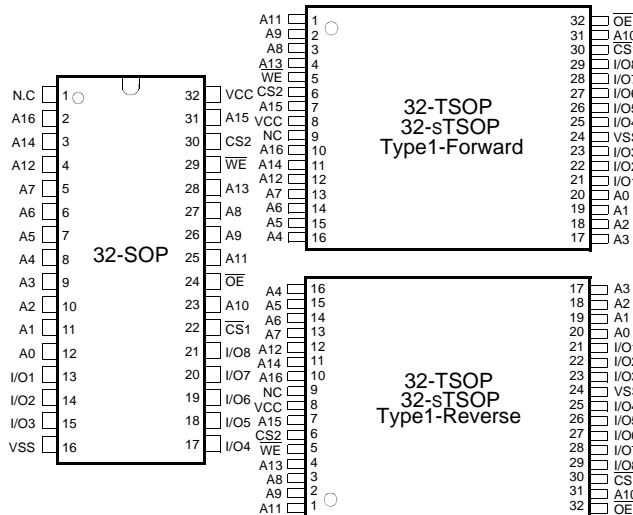
### GENERAL DESCRIPTION

The KM68V1000C and KM68U1000C families are fabricated by SAMSUNG's advanced CMOS process technology. The families support various operating temperature ranges and have various package types for user flexibility of system design. The families also supports low data retention voltage for battery back-up operation with low data retention current.

### PRODUCT FAMILY

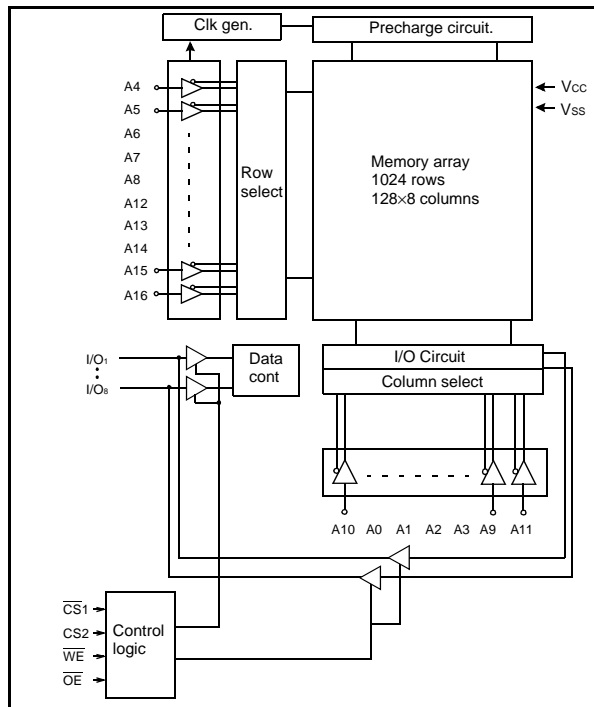
Product Family	Operating Temperature	Vcc Range(V)	Speed(ns)	Power Dissipation		PKG Type
				Standby (Isb1, Max)	Operating (Icc2, Max)	
KM68V1000CL-L	Commercial (0~70°C)	3.0~3.6V	70/100	10μA	35mA	32-SOP 32-TSOP1-F/R 32-sTSOP1-F/R
KM68U1000CL-L		2.7~3.3V	85/100			
KM68V1000CLE-L	Extended (-25~85°C)	3.0~3.6V	70/100			
KM68U1000CLE-L		2.7~3.3V	85/100			
KM68V1000CLI-L	Industrial (-40~85°C)	3.0~3.6V	70/100			
KM68U1000CLI-L		2.7~3.3V	85/100			

### PIN DESCRIPTION



Name	Function
$\overline{CS}_1, \overline{CS}_2$	Chip Select Inputs
$\overline{OE}$	Output Enable Input
$\overline{WE}$	Write Enable Input
A0~A16	Address Inputs
I/O1~I/O8	Data Inputs/Outputs
Vcc	Power
Vss	Ground
N.C	No Connection

### FUNCTIONAL BLOCK DIAGRAM



SAMSUNG ELECTRONICS CO., LTD. reserves the right to change products and specifications without notice.

## PRODUCT LIST

Commercial Temperature Products (0~70°C)		Extended Temperature Products (-25~85°C)		Industrial Temperature Products (-40~85°C)	
Part Name	Function	Part Name	Function	Part Name	Function
KM68V1000CLG-7L	32-SOP, 70ns, 3.3V	KM68V1000CLGE-7L	32-SOP, 70ns, 3.3V	KM68V1000CLGI-7L	32-SOP, 70ns, 3.3V
KM68V1000CLG-10L	32-SOP, 100ns, 3.3V	KM68V1000CLGE-10L	32-SOP, 100ns, 3.3V	KM68V1000CLGI-10L	32-SOP, 100ns, 3.3V
KM68V1000CLT-7L	32-TSOP F, 70ns, 3.3V	KM68V1000CLTE-7L	32-TSOP F, 70ns, 3.3V	KM68V1000CLTI-7L	32-TSOP F, 70ns, 3.3V
KM68V1000CLT-10L	32-TSOP F, 100ns, 3.3V	KM68V1000CLTE-10L	32-TSOP F, 100ns, 3.3V	KM68V1000CLTI-10L	32-TSOP F, 100ns, 3.3V
KM68V1000CLR-7L	32-TSOP R, 70ns, 3.3V	KM68V1000CLRE-7L	32-TSOP R, 70ns, 3.3V	KM68V1000CLRI-7L	32-TSOP R, 70ns, 3.3V
KM68V1000CLR-10L	32-TSOP R, 100ns, 3.3V	KM68V1000CLRE-10L	32-TSOP R, 100ns, 3.3V	KM68V1000CLRI-10L	32-TSOP R, 100ns, 3.3V
KM68U1000CLG-8L	32-SOP, 85ns, 3.0V	KM68U1000CLGE-8L	32-SOP, 85ns, 3.0V	KM68U1000CLGI-8L	32-SOP, 85ns, 3.0V
KM68U1000CLG-10L	32-SOP, 100ns, 3.0V	KM68U1000CLGE-10L	32-SOP, 100ns, 3.0V	KM68U1000CLGI-10L	32-SOP, 100ns, 3.0V
KM68U1000CLT-8L	32-TSOP F, 85ns, 3.0V	KM68U1000CLTE-8	32-TSOP F, 85ns, 3.0V	KM68U1000CLTI-8L	32-TSOP F, 85ns, 3.0V
KM68U1000CLT-10L	32-TSOP F, 100ns, 3.0V	KM68U1000CLTE-10L	32-TSOP F, 100ns, 3.0V	KM68U1000CLTI-10L	32-TSOP F, 100ns, 3.0V
KM68U1000CLR-8L	32-TSOP R, 85ns, 3.0V	KM68U1000CLRE-8	32-TSOP R, 85ns, 3.0V	KM68U1000CLRI-8L	32-TSOP R, 85ns, 3.0V
KM68U1000CLR-10L	32-TSOP R, 100ns, 3.0V	KM68U1000CLRE-10L	32-TSOP R, 100ns, 3.0V	KM68U1000CLRI-10L	32-TSOP R, 100ns, 3.0V
KM68V1000CLTG-7L	32-sTSOP F, 70ns, 3.3V	KM68V1000CLTGE-7L	32-sTSOP F, 70ns, 3.3V	KM68V1000CLTGI-7L	32-sTSOP F, 70ns, 3.3V
KM68V1000CLTG-10L	32-sTSOP F, 100ns, 3.3V	KM68V1000CLTGE-10L	32-sTSOP F, 100ns, 3.3V	KM68V1000CLTGI-10L	32-sTSOP F, 100ns, 3.3V
KM68V1000CLRG-7L	32-sTSOP R, 70ns, 3.3V	KM68V1000CLRGE-7L	32-sTSOP R, 70ns, 3.3V	KM68V1000CLRGI-7L	32-sTSOP R, 70ns, 3.3V
KM68V1000CLRG-10L	32-sTSOP R, 100ns, 3.3V	KM68V1000CLRGE-10L	32-sTSOP R, 100ns, 3.3V	KM68V1000CLRGI-10L	32-sTSOP R, 100ns, 3.3V
KM68U1000CLTG-8L	32-sTSOP F, 85ns, 3.0V	KM68U1000CLTGE-8L	32-sTSOP F, 85ns, 3.0V	KM68U1000CLTGI-8L	32-sTSOP F, 85ns, 3.0V
KM68U1000CLTG-10L	32-sTSOP F, 100ns, 3.0V	KM68U1000CLTGE-10L	32-sTSOP F, 100ns, 3.0V	KM68U1000CLTGI-10L	32-sTSOP F, 100ns, 3.0V
KM68U1000CLTG-8L	32-sTSOP R, 85ns, 3.0V	KM68U1000CLTGE-8L	32-sTSOP R, 85ns, 3.0V	KM68U1000CLTGI-8L	32-sTSOP R, 85ns, 3.0V
KM68U1000CLTG-10L	32-sTSOP R, 100ns, 3.0V	KM68U1000CLTGE-10L	32-sTSOP R, 100ns, 3.0V	KM68U1000CLTGI-10L	32-sTSOP R, 100ns, 3.0V

## FUNCTIONAL DESCRIPTION

CS <sub>1</sub>	CS <sub>2</sub>	OE	WE	I/O Pin	Mode	Power
H	X <sup>1)</sup>	X <sup>1)</sup>	X <sup>1)</sup>	High-Z	Deselected	Standby
X <sup>1)</sup>	L	X <sup>1)</sup>	X <sup>1)</sup>	High-Z	Deselected	Standby
L	H	H	H	High-Z	Output Disabled	Active
L	H	L	H	Dout	Read	Active
L	H	X <sup>1)</sup>	L	Din	Write	Active

1. X means don't care(Must be in high or low status.)

## ABSOLUTE MAXIMUM RATINGS<sup>1)</sup>

Item	Symbol	Ratings	Unit	Remark
Voltage on any pin relative to Vss	V <sub>IN</sub> , V <sub>OUT</sub>	-0.5 to V <sub>CC</sub> +0.5	V	-
Voltage on Vcc supply relative to	V <sub>CC</sub>	-0.3 to 4.6	V	-
Power Dissipation	P <sub>D</sub>	1.0	W	-
Storage temperature	T <sub>STG</sub>	-65 to 150	°C	-
Operating Temperature	T <sub>A</sub>	0 to 70	°C	KM68V1000CL/KM68U1000CL
		-25 to 85	°C	KM68V1000CLE/KM68U1000CLE
		-40 to 85	°C	KM68V1000CLI/KM68U1000CLI
Soldering temperature and time	T <sub>SOLDER</sub>	260°C, 10sec (Lead Only)	-	-

1. Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. Functional operation should be restricted to recommended operating condition. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

## RECOMMENDED DC OPERATING CONDITIONS<sup>1)</sup>

Item	Symbol	Product	Min	Typ	Max	Unit
Supply voltage	V <sub>CC</sub>	KM68V1000C Family KM68U1000C Family	3.0 2.7	3.3 3.0	3.6 3.3	V
Ground	V <sub>SS</sub>	All Family	0	0	0	V
Input high voltage	V <sub>IH</sub>	KM68V1000C, KM68U1000C Family	2.2	-	V <sub>CC</sub> +0.3 <sup>2)</sup>	V
Input low voltage	V <sub>IL</sub>	KM68V1000C, KM68U1000C Family	-0.3 <sup>3)</sup>	-	0.6	V

1. Commercial Product: T<sub>A</sub>=0 to 70°C, unless otherwise specified  
Extended Product: T<sub>A</sub>=-25 to 85°C, unless otherwise specified  
Industrial Product: T<sub>A</sub>=-40 to 85°C, unless otherwise specified
2. Overshoot: V<sub>CC</sub>+3.0V in case of pulse width ≤30ns
3. Undershoot: -3.0V in case of pulse width ≤30ns
4. Overshoot and undershoot is sampled, not 100% tested.

## CAPACITANCE<sup>1)</sup> (f=1MHz, T<sub>A</sub>=25°C)

Item	Symbol	Test Condition	Min	Max	Unit
Input capacitance	C <sub>IN</sub>	V <sub>IN</sub> =0V	-	6	pF
Input/Output capacitance	C <sub>IO</sub>	V <sub>IO</sub> =0V	-	8	pF

1. Capacitance is sampled, not 100% tested

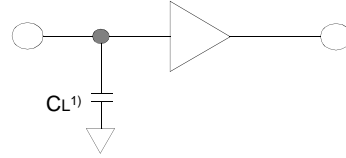
## DC AND OPERATING CHARACTERISTICS

Item	Symbol	Test Conditions	Min	Typ	Max	Unit
Input leakage current	I <sub>LI</sub>	V <sub>IN</sub> =V <sub>SS</sub> to V <sub>CC</sub>	-1	-	1	μA
Output leakage current	I <sub>LO</sub>	$\overline{CS}_1=V_{IH}$ or $CS_2=V_{IL}$ or $\overline{OE}=V_{IH}$ or $\overline{WE}=V_{IL}$ , V <sub>IO</sub> =V <sub>SS</sub> to V <sub>CC</sub>	-1	-	1	μA
Operating power supply	I <sub>CC</sub>	I <sub>IO</sub> =0mA, $\overline{CS}_1=V_{IL}$ , $CS_2=V_{IH}$ , V <sub>IN</sub> =V <sub>IL</sub> or V <sub>IH</sub> , Read	-	2	5	mA
Average operating current	I <sub>CC1</sub>	Cycle time=1μs, 100% duty, I <sub>IO</sub> =0mA, $\overline{CS}_1 \leq 0.2V$ , $CS_2 \geq V_{CC}-0.2V$ , V <sub>IN</sub> ≤0.2V or V <sub>IN</sub> ≥V <sub>CC</sub> -0.2V	Read	-	1.5	5
			Write	-	10	15
	I <sub>CC2</sub>	Cycle time=Min, 100% duty, I <sub>IO</sub> =0mA, $\overline{CS}_1=V_{IL}$ , $CS_2=V_{IH}$ , V <sub>IN</sub> =V <sub>IL</sub> or V <sub>IH</sub>	-	25	35	mA
Output low voltage	V <sub>OL</sub>	I <sub>OL</sub> =2.1mA	-	-	0.4	V
Output high voltage	V <sub>OH</sub>	I <sub>OH</sub> =-1.0mA	2.2	-	-	V
Standby Current(TTL)	I <sub>SB</sub>	$\overline{CS}_1=V_{IH}$ , $CS_2=V_{IL}$ , Other inputs=V <sub>IL</sub> or V <sub>IH</sub>	-	-	0.3	mA
Standby Current(CMOS)	I <sub>SB1</sub>	$\overline{CS}_1 \geq V_{CC}-0.2V$ , $CS_2 \geq V_{CC}-0.2V$ or $CS_2 \leq 0.2V$ , Other inputs=0~V <sub>CC</sub>	-	0.3	10	μA

## AC OPERATING CONDITIONS

### TEST CONDITIONS (Test Load and Input/Output Reference)

Input pulse level: 0.4 to 2.2V  
 Input rising and falling time: 5ns  
 Input and output reference voltage: 1.5V  
 Output load (see right):  $C_L = 100\text{pF} + 1\text{TTL}$



1. Including scope and jig capacitance

## AC CHARACTERISTICS

(Commercial product:  $T_A = 0$  to  $70^\circ\text{C}$ , Extended product:  $T_A = -25$  to  $85^\circ\text{C}$ , Industrial product:  $T_A = -40$  to  $85^\circ\text{C}$   
 KM68V1000C Family:  $V_{CC} = 3.0 \sim 3.6\text{V}$ , KM68U1000C Family:  $V_{CC} = 2.7 \sim 3.3\text{V}$ )

Parameter List		Symbol	Speed Bins						Units
			70ns		85ns		100ns		
			Min	Max	Min	Max	Min	Max	
Read	Read cycle time	tRC	70	-	85	-	100	-	ns
	Address access time	tAA	-	70	-	85	-	100	ns
	Chip select to output	tCO1, tCO2	-	70	-	85	-	100	ns
	Output enable to valid output	tOE	-	35	-	40	-	50	ns
	Chip select to low-Z output	tLZ	10	-	10	-	10	-	ns
	Output enable to low-Z output	tOLZ	5	-	5	-	5	-	ns
	Chip disable to high-Z output	tHZ	0	25	0	25	0	30	ns
	Output disable to high-Z output	tOHZ	0	25	0	25	0	30	ns
	Output hold from address change	tOH	10	-	15	-	15	-	ns
Write	Write cycle time	tWC	70	-	85	-	100	-	ns
	Chip select to end of write	tCW	60	-	70	-	80	-	ns
	Address set-up time	tAS	0	-	0	-	0	-	ns
	Address valid to end of write	tAW	60	-	70	-	80	-	ns
	Write pulse width	tWP	55	-	60	-	70	-	ns
	Write recovery time	tWR	0	-	0	-	0	-	ns
	Write to output high-Z	tWHZ	0	25	0	30	0	30	ns
	Data to write time overlap	tDW	30	-	35	-	40	-	ns
	Data hold from write time	tDH	0	-	0	-	0	-	ns
	End write to output low-Z	tOW	5	-	5	-	5	-	ns

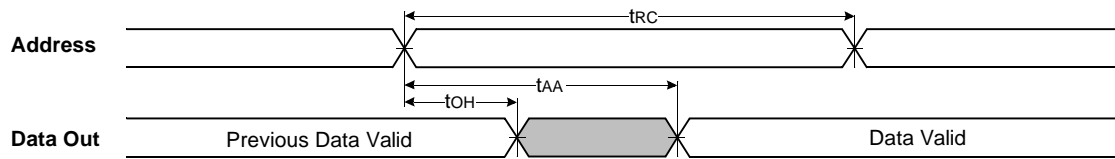
## DATA RETENTION CHARACTERISTICS

Item	Symbol	Test Condition <sup>1)</sup>	Min	Typ	Max	Unit
V <sub>CC</sub> for data retention	V <sub>DR</sub>	$\overline{CS_1} \geq V_{CC} - 0.2\text{V}$	2.0	-	3.6	V
Data retention current	I <sub>DR</sub>	$V_{CC} = 3.0\text{V}$ , $\overline{CS_1} \geq V_{CC} - 0.2\text{V}$ , $CS_2 \geq V_{CC} - 0.2\text{V}$ , or $CS_2 \leq 0.2\text{V}$	-	0.3	5	$\mu\text{A}$
Data retention set-up time	t <sub>SDR</sub>	See data retention waveform	0	-	-	ms
Recovery time	t <sub>RDR</sub>		5	-	-	

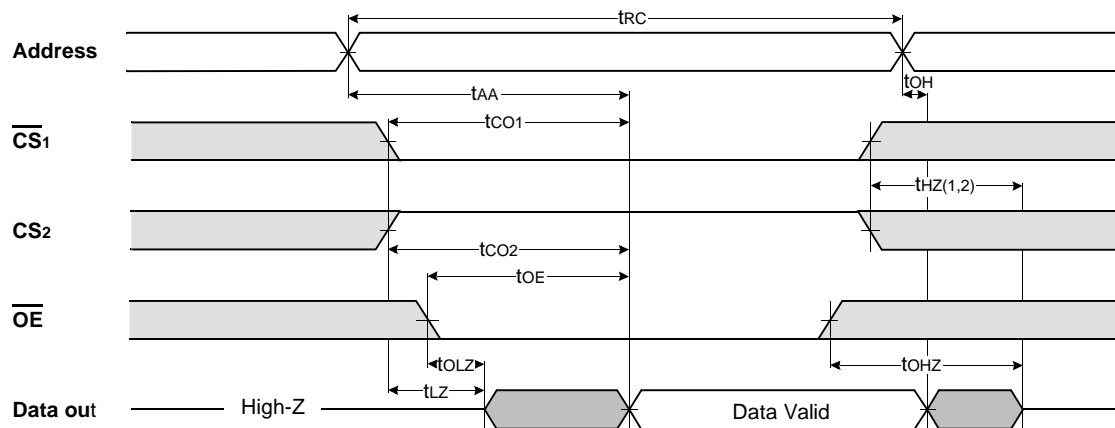
1.  $CS_1 \geq V_{CC} - 0.2\text{V}$ ,  $CS_2 \geq V_{CC} - 0.2\text{V}$ , or  $CS_2 \leq 0.2\text{V}$

## TIMMING DIAGRAMS

**TIMING WAVEFORM OF READ CYCLE(1)** (Address Controlled,  $\overline{CS}=\overline{OE}=V_{IL}$ ,  $\overline{WE}=V_{IH}$ )



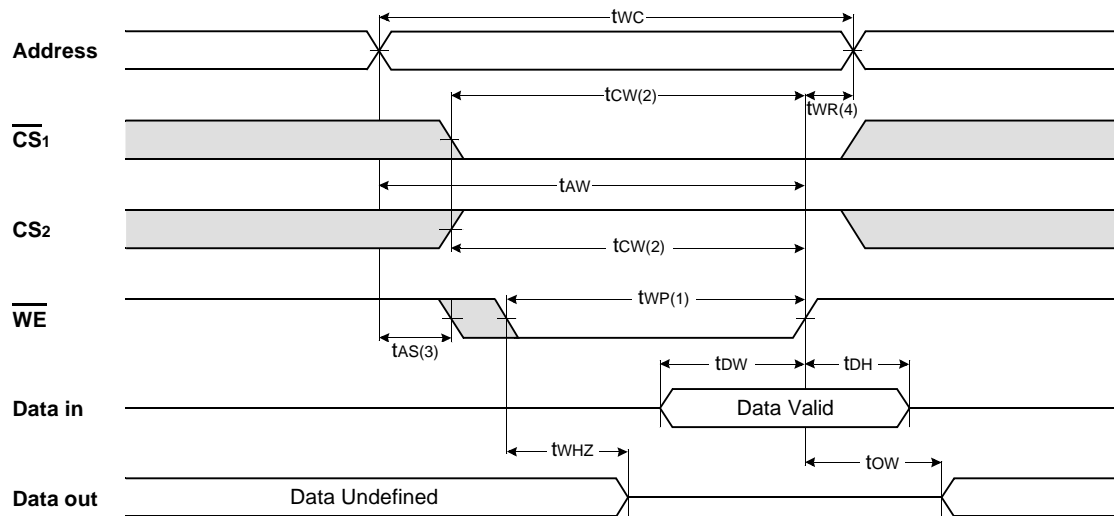
**TIMING WAVEFORM OF READ CYCLE(2)** ( $\overline{WE}=V_{IH}$ )



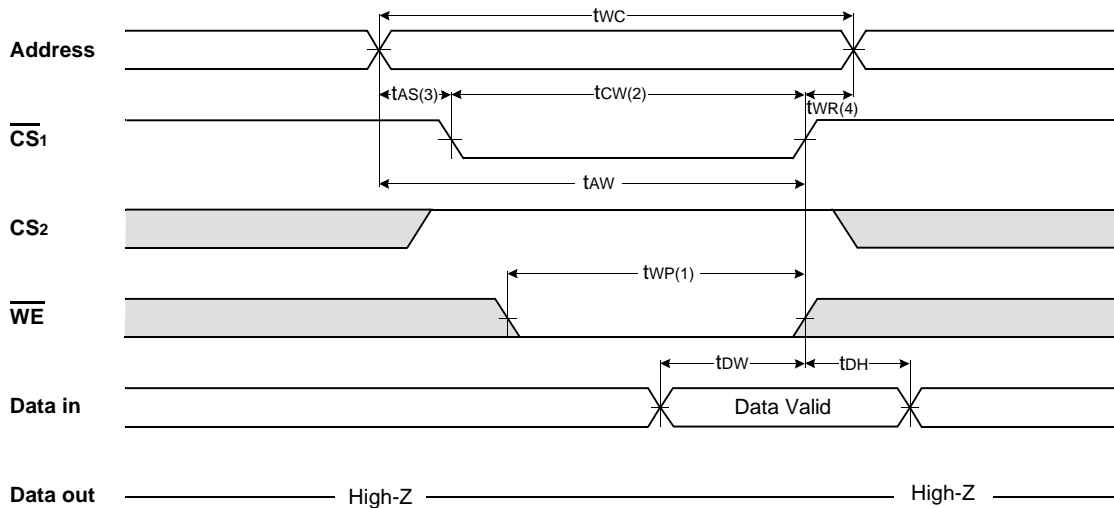
### NOTES (READ CYCLE)

1.  $t_{HZ}$  and  $t_{OHZ}$  are defined as the time at which the outputs achieve the open circuit conditions and are not referenced to output voltage levels.
2. At any given temperature and voltage condition,  $t_{HZ}(\text{Max.})$  is less than  $t_{LZ}(\text{Min.})$  both for a given device and from device to device interconnection.

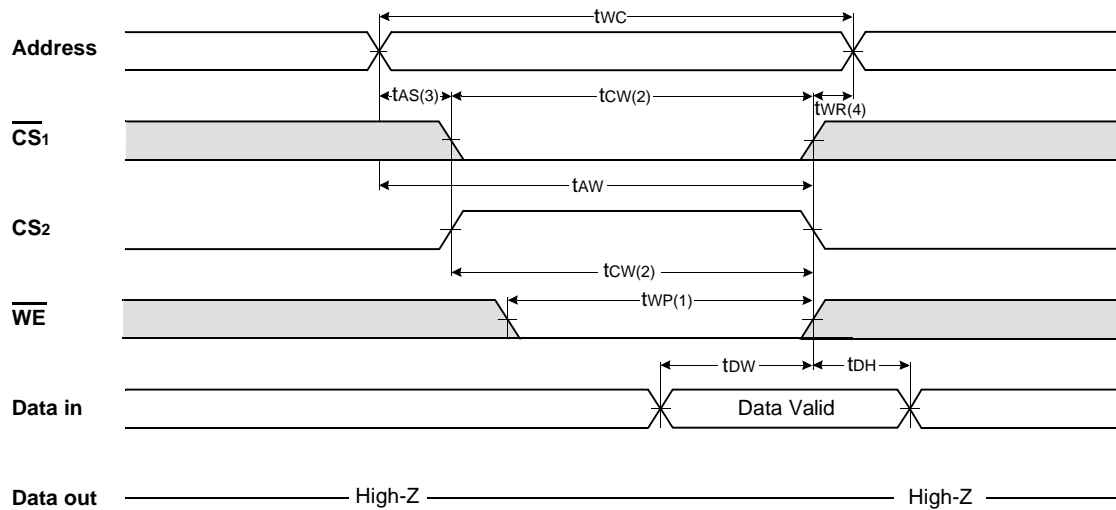
**TIMING WAVEFORM OF WRITE CYCLE(1) ( $\overline{WE}$  Controlled)**



**TIMING WAVEFORM OF WRITE CYCLE(2) ( $\overline{CS1}$  Controlled)**



## TIMING WAVEFORM OF WRITE CYCLE(3) (CS<sub>2</sub> Controlled)

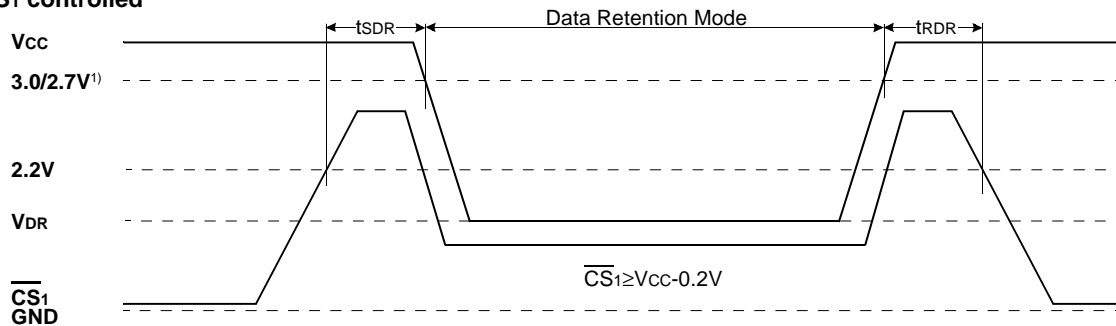


### NOTES (WRITE CYCLE)

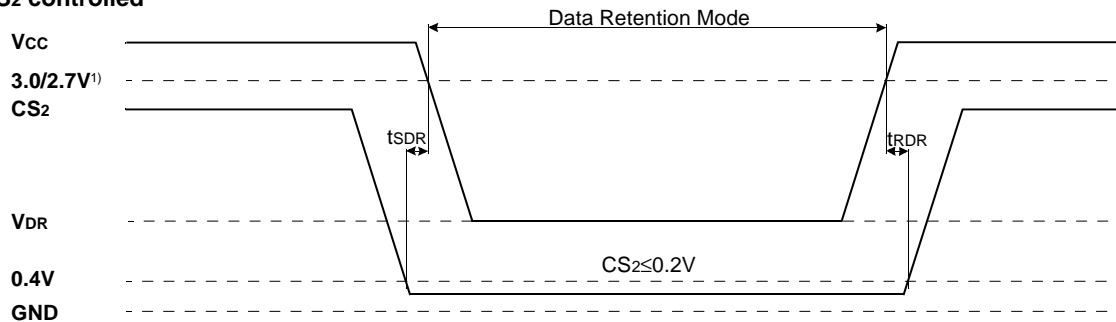
1. A write occurs during the overlap of a low  $\overline{CS_1}$ , a high CS<sub>2</sub> and a low  $\overline{WE}$ . A write begins at the latest transition among  $\overline{CS_1}$  goes low, CS<sub>2</sub> going high and  $\overline{WE}$  going low. A write ends at the earliest transition among CS<sub>1</sub> going high, CS<sub>2</sub> going low and  $\overline{WE}$  going high, tWP is measured from the beginning of write to the end of write.
2. tCW is measured from the CS<sub>1</sub> going low or CS<sub>2</sub> going high to the end of write.
3. tAS is measured from the address valid to the beginning of write.
4. tWR is measured from the end of write to the address change. tWR(1) applied in case a write ends as  $\overline{CS_1}$  or  $\overline{WE}$  going high tWR(2) applied in case a write ends as CS<sub>2</sub> going to low.

## DATA RETENTION WAVE FORM

### CS<sub>1</sub> controlled



### CS<sub>2</sub> controlled



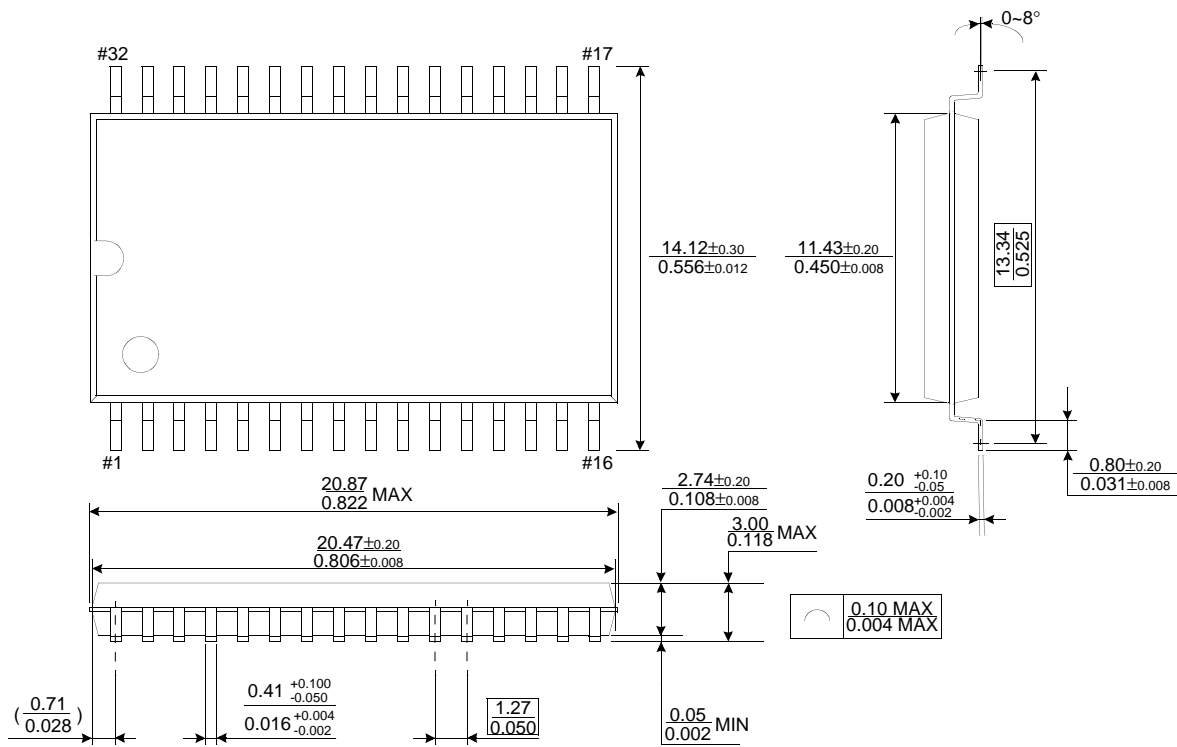
1. 3.0V for KM68V1000C Family, 2.7V for KM68U1000C Family



## PACKAGE DIMENSIONS

Units: millimeter(inch)

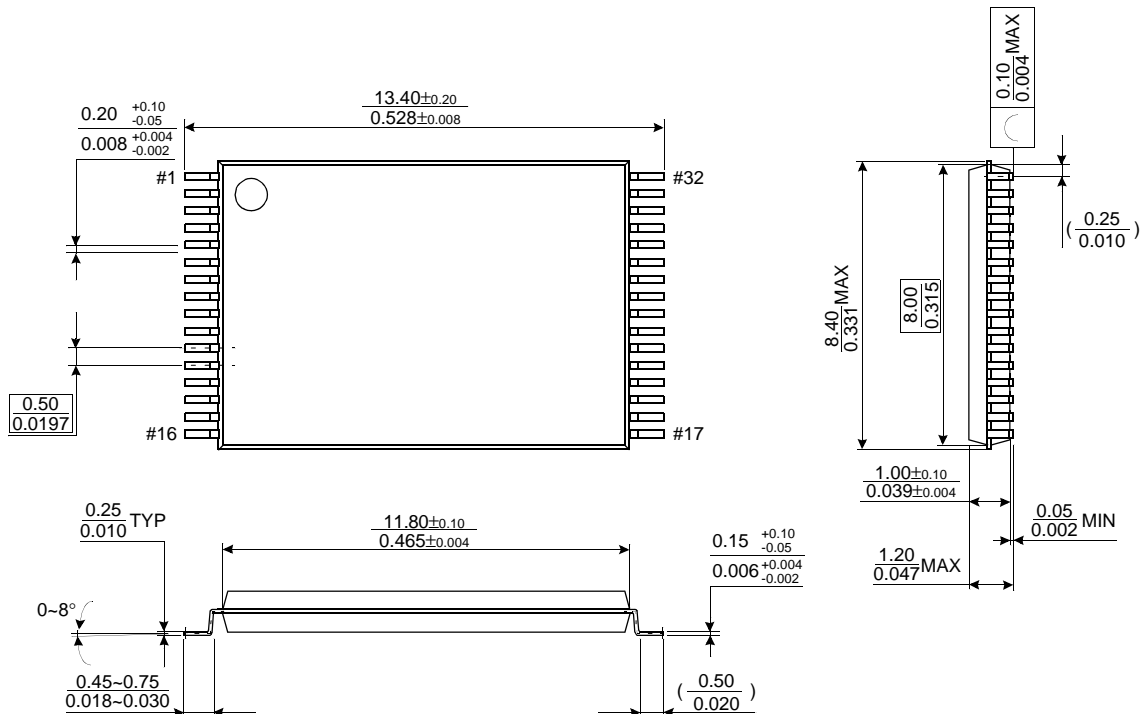
### 32 PIN PLASTIC SMALL OUTLINE PACKAGE (525mil)



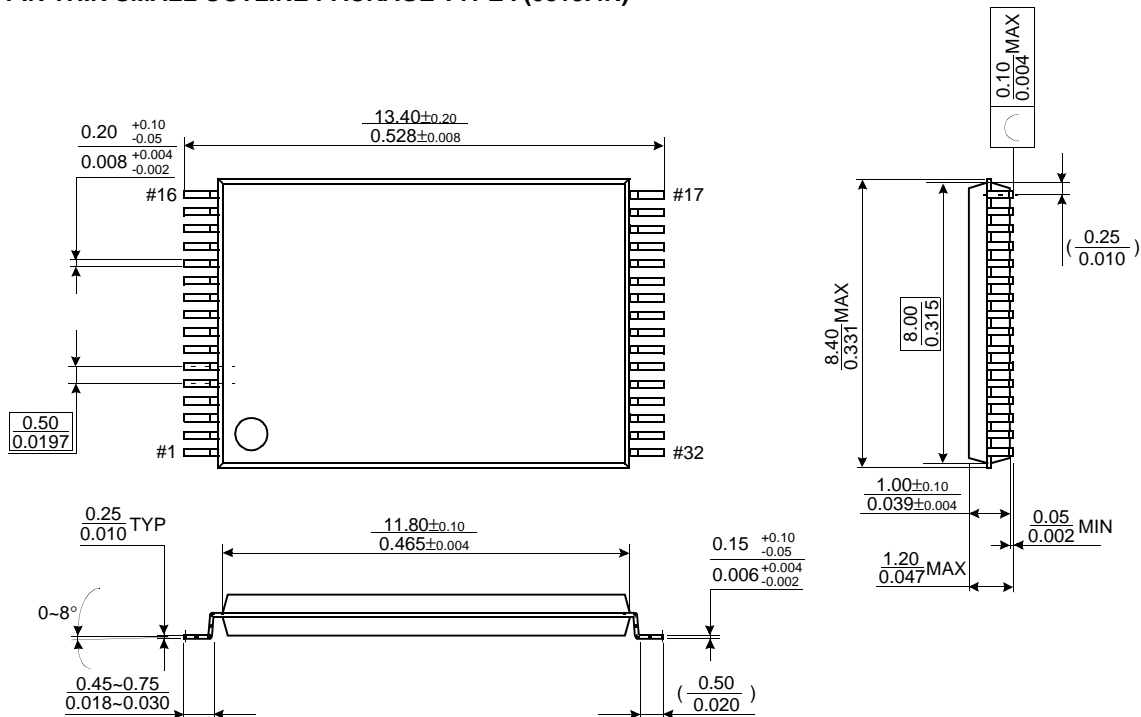
## PACKAGE DIMENSIONS

Units: millimeter(inch)

### 32 PIN THIN SMALL OUTLINE PACKAGE TYPE I (0813.4F)



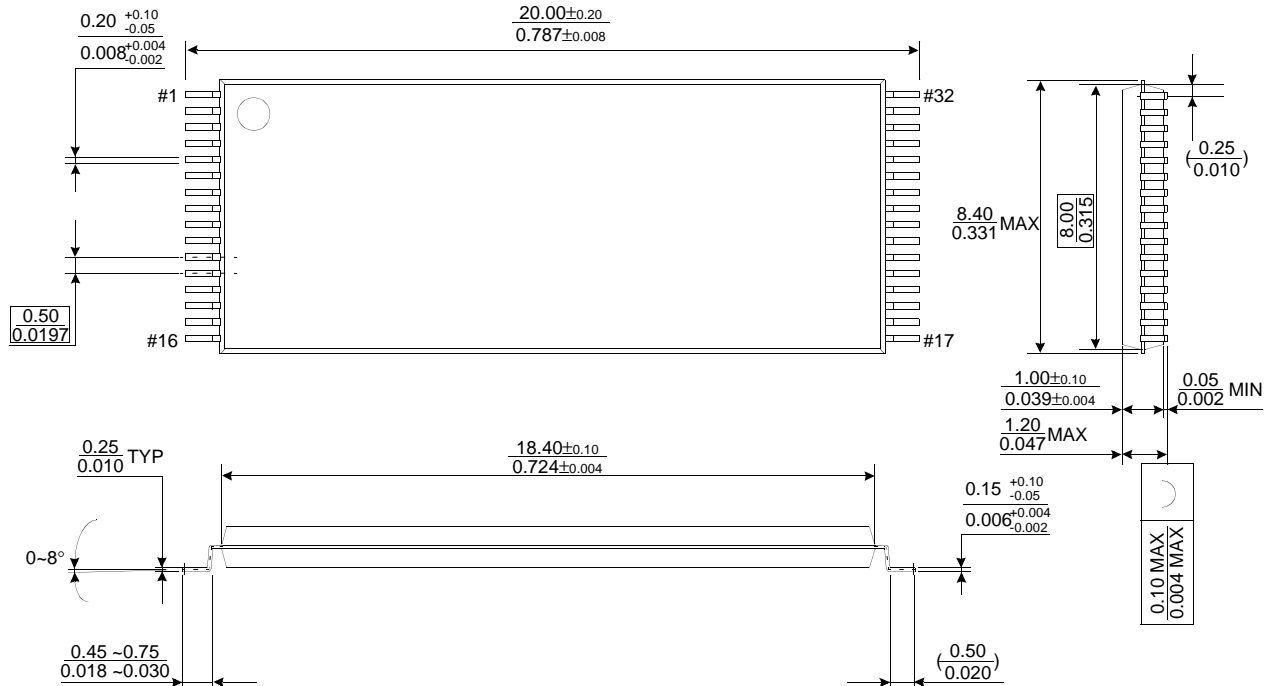
### 32 PIN THIN SMALL OUTLINE PACKAGE TYPE I (0813.4R)



## PACKAGE DIMENSIONS

Units: millimeter(inch)

### 32 PIN THIN SMALL OUTLINE PACKAGE TYPE I (0820F)



### 32 PIN THIN SMALL OUTLINE PACKAGE TYPE I (0820R)

